



SLOVENSKI STANDARD
SIST EN 61646:2008
01-december-2008

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SIST EN 61646:2001

Tankoplastni prizemni fotonapetostni (PV) moduli - Ocena zasnove in odobritev tipa (IEC 61646:2008)

Thin-film terrestrial photovoltaic (PV) modules - Design qualification and type approval

Terrestrische Dünnschicht-Photovoltaik (PV)-Module - Bauarteignung und Bauartzulassung

ITeh STANDARD PREVIEW
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Modules photovoltaïques (PV) en couches minces pour application terrestre - Qualification de la conception et homologation

<https://standards.iteh.ai/catalog/standards/sist/3be06ca9-89c7-4858-9abb-f5a419deecb8/sist-en-61646-2008>

Ta slovenski standard je istoveten z: EN 61646:2008

ICS:

27.160 Ú[} } æ } ^ i * æ Solar energy engineering

SIST EN 61646:2008 **en,fr,de**

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EUROPEAN STANDARD
NORME EUROPÉENNE
EUROPÄISCHE NORM

EN 61646

August 2008

ICS 27.160

Supersedes EN 61646:1997

English version

**Thin-film terrestrial photovoltaic (PV) modules -
Design qualification and type approval
(IEC 61646:2008)**

Modules photovoltaïques (PV)
en couches minces
pour application terrestre -
Qualification de la conception
et homologation
(CEI 61646:2008)

Terrestrische Dünnschicht-Photovoltaik
(PV)-Module -
Bauartegnung und Bauartzulassung
(IEC 61646:2008)

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This European Standard was approved by CENELEC on 2008-06-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Bulgaria, Cyprus, the Czech Republic, Denmark, Estonia, Finland, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, the Netherlands, Norway, Poland, Portugal, Romania, Slovakia, Slovenia, Spain, Sweden, Switzerland and the United Kingdom.

CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

Foreword

The text of document 82/512/FDIS, future edition 2 of IEC 61646, prepared by IEC TC 82, Solar photovoltaic energy systems, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 61646 on 2008-06-01.

This European Standard supersedes EN 61646:1997.

EN 61646:2008 includes the following significant technical changes with respect to EN 61646:1997:

The major change is in the pass/fail criteria. It no longer relies on meeting a plus/minus criterion before and after each test, but rather on meeting the rated power after all of the tests have been completed and the modules have been light-soaked. This was done to eliminate the technology-specific preconditioning necessary to accurately measure the changes caused by the test. (Some modules lose power in light while others lose power during dark heat.) Since all modules must work after exposure to light, this seemed like a good approach and will streamline the test procedure, hopefully reducing the testing cost.

- updated normative references;
- added a definition of “minimum value of maximum output power”;
- modified the wording in major visual defects to allow some bending and misalignment without failure;
- added requirements to the report from EN ISO/IEC 17025;
- removed the “Twist Test” as was done from EN 61215, since no one has ever failed this test;
- made the pass/fail criteria for insulation resistance and wet leakage current dependent on the module area;
- added the temperature coefficient of power (δ) to the required measurements;
- modified temperature coefficient section to allow for measurements under natural sunlight or a solar simulator;
- deleted reference plate method from NOCT;
- added apparatus sections to those test procedures that did not have apparatus sections in EN 61646:1997;
- rewrote the hot-spot test;
- eliminated edge dip method from wet leakage current test;
- changed mechanical load test to 3 cycles to be consistent with other standards;
- added bypass diode thermal test.

The following dates were fixed:

- latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2009-03-01
- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 2011-06-01

Annex ZA has been added by CENELEC.

Endorsement notice

The text of the International Standard IEC 61646:2008 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 60904-5	NOTE	Harmonized as EN 60904-5:1995 (not modified).
IEC 60904-8	NOTE	Harmonized as EN 60904-8:1998 (not modified).

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Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60068-1	- ¹⁾	Environmental testing - Part 1: General and guidance	EN 60068-1	1994 ²⁾
IEC 60068-2-21	- ¹⁾	Environmental testing - Part 2-21: Tests - Test U: Robustness of terminations and integral mounting devices	EN 60068-2-21	2006 ²⁾
IEC 60068-2-78	2001	Environmental testing - Part 2-78: Tests - Test Cab: Damp heat, steady state	EN 60068-2-78	2001 ²⁾
IEC 60410	- ¹⁾	Sampling plans and procedures for inspection - by attributes	-	-
IEC 60721-2-1	- ¹⁾	Classification of environmental conditions - Part 2-1: Environmental conditions appearing in nature - Temperature and humidity	HD 478.2.1 S1	1989 ²⁾
IEC 60891	- ¹⁾	Procedures for temperature and irradiance corrections to measured I-V characteristics of crystalline silicon photovoltaic devices	EN 60891	1994 ²⁾
IEC 60904-1	2006	Photovoltaic devices - Part 1: Measurement of photovoltaic current- voltage characteristics	EN 60904-1	2006 ²⁾
IEC 60904-2	- ¹⁾	Photovoltaic devices - Part 2: Requirements for reference solar devices	EN 60904-2	2007 ²⁾
IEC 60904-3	- ¹⁾	Photovoltaic devices - Part 3: Measurement principles for terrestrial photovoltaic (PV) solar devices with reference spectral irradiance data	EN 60904-3	2008 ²⁾
IEC 60904-7	- ¹⁾	Photovoltaic devices - Part 7: Computation of spectral mismatch error introduced in the testing of a photovoltaic device	EN 60904-7	1998 ²⁾
IEC 60904-9	- ¹⁾	Photovoltaic devices - Part 9: Solar simulator performance requirements	EN 60904-9	2007 ²⁾
IEC 60904-10	- ¹⁾	Photovoltaic devices - Part 10: Methods of linearity measurement	EN 60904-10	1998 ²⁾
IEC 61215	- ¹⁾	Crystalline silicon terrestrial photovoltaic (PV) modules - Design qualification and type approval	EN 61215	2005 ²⁾

¹⁾ Undated reference.

²⁾ Valid edition at date of issue.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
ISO/IEC 17025	- ¹⁾	General requirements for the competence of testing and calibration laboratories	EN ISO/IEC 17025	2005 ²⁾

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IEC 61646

Edition 2.0 2008-05

INTERNATIONAL STANDARD

NORME INTERNATIONALE

Thin-film terrestrial photovoltaic (PV) modules – Design qualification and type approval

(standards.iteh.ai)

Modules photovoltaïques (PV) en couches minces pour application terrestre –
Qualification de la conception et homologation

INTERNATIONAL
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COMMISSION

COMMISSION
ELECTROTECHNIQUE
INTERNATIONALE

PRICE CODE
CODE PRIX



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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**THIN-FILM TERRESTRIAL PHOTOVOLTAIC (PV) MODULES –
DESIGN QUALIFICATION AND TYPE APPROVAL**

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
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International Standard IEC 61646 has been prepared by IEC technical committee 82: Solar photovoltaic energy systems.

This second edition cancels and replaces the first edition published in 1996. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

The major change is in the pass/fail criteria. It no longer relies on meeting a plus/minus criterion before and after each test, but rather on meeting the rated power after all of the tests have been completed and the modules have been light-soaked. This was done to eliminate the technology-specific preconditioning necessary to accurately measure the changes caused by the test. (Some modules lose power in light while others lose power during dark heat.) Since all modules must work after exposure to light, this seemed like a good approach and will streamline the test procedure, hopefully reducing the testing cost.

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